

Title (en)  
METHODS AND DEVICES FOR ANALYSING A DEFORMABLE OBJECT

Title (de)  
VERFAHREN UND VORRICHTUNGEN ZUR UNTERSUCHUNG EINES DEFORMIERBAREN OBJEKTS

Title (fr)  
PROCEDE ET DISPOSITIFS POUR EXAMINER UN OBJET DEFORMABLE

Publication  
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Application  
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Abstract (en)  
[origin: WO2005045400A1] The invention relates to methods for analysing at least one deformable object (O) in a liquid suspension, comprising the steps: generation of an electric positioning field and positioning of the object (O) in a minimum potential of the positioning field; generation of an electric deformation field in such a way that a deformation force is exerted on the object (O); and detection of at least one dielectric, geometric or optical characteristic of said object (O). According to the invention, the positioning field is generated in a compartment (12) of a fluidic microsystem (10) and the positioning of the object (O) in a freely suspended state takes place in a contactless manner. The invention also relates to measuring apparatus that is used to carry out said method.

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Citation (search report)  
See references of WO 2005045400A1

Citation (examination)  
SCHNELLE T.H. ET AL: "Paired microelectrode system: dielectrophoretic particle sorting and force calibration", JOURNAL OF ELECTROSTATICS, vol. 47, 15 December 1998 (1998-12-15) - 22 February 1999 (1999-02-22), pages 121 - 132, XP004179202

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